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| Notice of References Cited | Application/Control No. 10/522,572 | Applicant(s)/Patent Under Reexamination LEE ET AL. | |
| | Examiner Kevin Quarterman | Art Unit 2879 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------|----------------|
| * | A | US-2003/0090190 A1 | 05-2003 | Takai et al. | 313/311 |
| * | B | US-6,774,548 B2 | 08-2004 | Fran et al. | 313/309 |
| * | C | US-6,741,019 B1 | 05-2004 | Filas et al. | 313/355 |
| * | D | US-6,538,367 B1 | 03-2003 | Choi et al. | 313/309 |
| * | E | US-6,515,415 B1 | 02-2003 | Han et al. | 313/496 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------------|----------------|
| | N | KR 10-2002-0041665 | 03-2002 | Korea | Cho et al. | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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